

Notice of References Cited

Application/Control No.

10/077,924

Applicant(s)/Patent Under
Reexamination
NOHARA ET AL.

Examiner

Hai H. Huynh

Art Unit

3747

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,390,041 B2	05-2002	Nakamura et al.	123/90.15
	B	US-6,408,806 B2	06-2002	Sugiyama et al.	123/90.15
	C	US-6,499,454 B2	12-2002	Miyazato et al.	123/90.31
	D	US-6,513,467 B2	02-2003	Nohara et al.	123/90.15
	E	US-6,550,436 B2	04-2003	Nohara et al.	123/90.16
	F	US-6,578,534 B2	06-2003	Nohara et al.	123/90.16
	G	US-6,615,775 B2	09-2003	Takemura et al.	123/90.15
	H	US-6,626,135 B2	09-2003	Takemura et al.	123/90.17
	I	US-6,647,935 B2	11-2003	Aoyama et al.	123/90.16
	J	US-6,659,054 B2	12-2003	Sugiyama et al.	123/90.16
	K	US-2002/0185100 A1	12-2002	Matsumoto et al.	123/184.21
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.